L Number	Hits	Search Text	DB	Time stamp
1	5191	(250/492.22,492.2,492.3).CCLS.	USPAT; US-PGPUB;	2004/04/04 14:19
2	20407	((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4	EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/04 14:20
3	511	(((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near4 signal near4 stor\$4)	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/04 14:49
4	425	((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4 near4 signal near4 stor\$4)) and control near1 signal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/04
5	425		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/04 14:22
6	35	(((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near4 signal near4 stor\$4)) and (control near1 signal)) and ((storage or store or	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:27
8	2	<pre>(charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near4 signal near4 stor\$4)) and (control near1 signal)) and ((storage or store or storing) near1 (control near signal))) and (shift near register\$4)) and</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:24
7	10	<pre>((plurality or multiple) near4 beam) ((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near4 signal near4 stor\$4)) and (control near1 signal)) and ((storage or store or storing) near1 (control near signal))) and (shift near register\$4)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:25
9	3		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:28
10	35	<pre>(((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control adj signal adj (storage or stor\$3))</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:29
11	14	<pre>((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control adj signal adj (storage or stor\$3))) and (deflect\$4 near2 control\$4)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04
12	1	(((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control adj signal adj (storage or stor\$3))) and (deflect\$4 near2 control\$4)) and ((250/492.22,492.2,492.3).CCLS.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:32

	6071	1 / / 3 4	IICDAM.	2004/04/04
13	6071	((electron or charged-particle or (charged adj particle)) near (beam or expos\$4)) and deflector	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/04 14:33
14	3551	(((electron or charged-particle or (charged adj particle)) near (beam or	IBM_TDB USPAT; US-PGPUB;	2004/04/04
		expos\$4)) and deflector) and (wafer or substrate or sample)	EPO; JPO; DERWENT; IBM TDB	
15	973	<pre>((((electron or charged-particle or (charged adj particle)) near (beam or expos\$4)) and deflector) and (wafer or substrate or sample)) and (deflect\$5 near2 control\$4)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/04 14:34
16	345	<pre>(((((electron or charged-particle or (charged adj particle)) near (beam or expos\$4)) and deflector) and (wafer or substrate or sample)) and (deflect\$5 near2 control\$4)) and (control\$4 near signal)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:40
18	2	<pre>(((((((electron or charged-particle or (charged adj particle)) near (beam or expos\$4)) and deflector) and (wafer or substrate or sample)) and (deflect\$5 near2 control\$4)) and (control\$4 near signal)) and (control\$4 near signal near storage)) and (stor\$4 near5 deflect\$4)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:36
17	3	<pre>((((((electron or charged-particle or (charged adj particle)) near (beam or expos\$4)) and deflector) and (wafer or substrate or sample)) and (deflect\$5 near2 control\$4)) and (control\$4 near signal)) and (control\$4 near signal near storage)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:40
19	703	<pre>((((electron or charged-particle or (charged adj particle)) near (beam or expos\$4)) and deflector) and (wafer or substrate or sample)) and (control\$4 near signal)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/04 14:40
20	5		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04
21	17	Hashimoto near Shin-Ichi	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:41
22	6121	<pre>(((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near2 signal)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:50
23	103	<pre>((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near2 signal)) and (stor\$4 near ((control or deflect\$4) near2 (output or signal)))</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04
24	37	<pre>(((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near2 signal)) and (stor\$4 near ((control or deflect\$4) near2 (output or signal)))) and (deflect\$5 near control\$4)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:51

25	16	<pre>(charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near2 signal)) and (stor\$4 near ((control or deflect\$4) near2 (output or signal))))</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:52
26	10	and (deflect\$5 near control\$4)) and (substrate or wafer or semiconductor) ((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near2 signal)) and (stor\$4 near ((control or deflect\$4) near2 (output or signal)))) and (deflect\$5 near control\$4)) and (substrate or wafer or semiconductor)) and (electrode or deflector)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 14:52

L	Hits	Search Text	DB	Time stamp
Number		(050/400,00,400,0,400,0), ggra	IIGDAM -	2004/04/04
1	5191	(250/492.22,492.2,492.3).CCLS.	USPAT; US-PGPUB;	2004/04/04 14:19
			EPO; JPO;	
			DERWENT;	
_	00407		<pre>IBM_TDB USPAT;</pre>	2004/04/04
2	20407	((electron or charged-particle or (charged adj particle))near beam) and	US-PGPUB;	16:49
		deflect\$4 and control\$4	EPO; JPO;	10.15
		40220007. 4114 00102027	DERWENT;	
			IBM_TDB	
3	511	(((electron or charged-particle or	USPAT; US-PGPUB;	2004/04/04 14:49
ļ	,	(charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4	EPO; JPO;	14:49
		near4 signal near4 stor\$4)	DERWENT;	
		near brynar noar boor, t	IBM TDB	
4	425	((((electron or charged-particle or	USPAT;	2004/04/04
		(charged adj particle))near beam) and	US-PGPUB;	14:22
		deflect\$4 and control\$4) and (control\$4	EPO; JPO; DERWENT;	
		near4 signal near4 stor\$4)) and control near1 signal	IBM TDB	
5	425	nearl signal ((((electron or charged-particle or	USPAT;	2004/04/04
•	125	(charged adj particle)) near beam) and	US-PGPUB;	14:22
		deflect\$4 and control\$4) and (control\$4	EPO; JPO;	
		near4 signal near4 stor\$4)) and (control	DERWENT;	
	3.5	near1 signal)	IBM_TDB USPAT;	2004/04/04
6	35	(((((electron or charged-particle or (charged adj particle))near beam) and	USPAT; US-PGPUB;	14:27
		deflect\$4 and control\$4) and (control\$4	EPO; JPO;	
		near4 signal near4 stor\$4)) and (control	DERWENT;	
		near1 signal)) and ((storage or store or	IBM_TDB	:
	_	storing) near1 (control near signal))	ucpam.	2004/04/04
8	2	(((((((electron or charged-particle or (charged adj particle))near beam) and	USPAT; US-PGPUB;	14:24
i		(charged ad) particle//hear beam/ and deflect\$4 and control\$4) and (control\$4	EPO; JPO;	11.21
		near4 signal near4 stor\$4)) and (control	DERWENT;	
		near1 signal)) and ((storage or store or	IBM_TDB	
		storing) near1 (control near signal)))		
		and (shift near register\$4)) and		
7	10	((plurality or multiple) near4 beam) ((((((electron or charged-particle or	USPAT;	2004/04/04
7	10	(charged adj particle)) near beam) and	US-PGPUB;	14:25
		deflect\$4 and control\$4) and (control\$4	EPO; JPO;	
		near4 signal near4 stor\$4)) and (control	DERWENT;]
		nearl signal)) and ((storage or store or	IBM_TDB	1
		<pre>storing) near1 (control near signal))) and (shift near register\$4)</pre>		
9	2	and (shift hear register;4) ((((((electron or charged-particle or	USPAT;	2004/04/04
) 	1	(charged adj particle)) near beam) and	US-PGPUB;	14:28
		deflect\$4 and control\$4) and (control\$4	EPO; JPO;	
	1	near4 signal near4 stor\$4)) and (control	DERWENT;	1
		near1 signal)) and ((storage or store or storing) near1 (control near signal)))	IBM_TDB	
		and ((250/492.22,492.2,492.3).CCLS.)		
10	35	1	USPAT;	2004/04/04
**		(charged adj particle)) near beam) and	US-PGPUB;	14:29
		deflect\$4 and control\$4) and (control adj	EPO; JPO;	
		signal adj (storage or stor\$3))	DERWENT; IBM TDB	
11	1 4	((((electron or charged-particle or	USPAT;	2004/04/04
11	14	((((electron or charged-particle of (charged adj particle)) near beam) and	US-PGPUB;	14:31
		deflect\$4 and control\$4) and (control adj	EPO; JPO;	
		signal adj (storage or stor\$3))) and	DERWENT;	
		(deflect\$4 near2 control\$4)	IBM_TDB	2004/04/04
12	1	(((((electron or charged-particle or	USPAT;	2004/04/04
		(charged adj particle)) near beam) and deflect\$4 and control\$4) and (control adj	US-PGPUB; EPO; JPO;	14.34
		signal adj (storage or stor\$3))) and	DERWENT;	
		(deflect\$4 near2 control\$4)) and	IBM_TDB	
		((250/492.22,492.2,492.3).CCLS.)		<u></u>

				0004/04/04
13	6071	((electron or charged-particle or (charged adj particle)) near (beam or	USPAT; US-PGPUB;	2004/04/04 14:33
		expos\$4)) and deflector	EPO; JPO; DERWENT;	
			IBM_TDB	0004/04/04
14	3551	(((electron or charged-particle or	USPAT;	2004/04/04
		(charged adj particle)) near (beam or expos\$4)) and deflector) and (wafer or	US-PGPUB; EPO; JPO;	14:34
		substrate or sample)	DERWENT;	
		Substitute of Sampie,	IBM TDB	
15	973	((((electron or charged-particle or	USPAT;	2004/04/04
		(charged adj particle)) near (beam or	US-PGPUB;	14:34
		expos\$4)) and deflector) and (wafer or	EPO; JPO;	
		substrate or sample)) and (deflect\$5	DERWENT;	
1.0	345	<pre>near2 control\$4) (((((electron or charged-particle or</pre>	IBM_TDB USPAT;	2004/04/04
16	345	(((((election of charged-particle of charged adj particle)) near (beam or	US-PGPUB;	14:40
		expos\$4)) and deflector) and (wafer or	EPO; JPO;	
		substrate or sample)) and (deflect\$5	DERWENT;	
		near2 control\$4)) and (control\$4 near	IBM_TDB	
1		signal)		2004/04/04
18	2	((((((electron or charged-particle or	USPAT; US-PGPUB;	2004/04/04 14:36
		(charged adj particle)) near (beam or expos\$4)) and deflector) and (wafer or	EPO; JPO;	14.50
		substrate or sample)) and (deflect\$5	DERWENT;	
		near2 control\$4)) and (control\$4 near	IBM_TDB	
		signal)) and (control\$4 near signal near		,
	_	storage)) and (stor\$4 near5 deflect\$4)	TICDIM.	2004/04/04
17	3	(((((velectron or charged-particle or (charged adj particle)) near (beam or	USPAT; US-PGPUB;	14:40
		expos\$4)) and deflector) and (wafer or	EPO; JPO;	11.10
		substrate or sample)) and (deflect\$5	DERWENT;	
•		near2 control\$4)) and (control\$4 near	IBM_TDB	
		signal)) and (control\$4 near signal near		
	700	storage)	USPAT;	2004/04/04
19	703	((((electron or charged-particle or (charged adj particle)) near (beam or	US-PGPUB;	14:40
		expos\$4)) and deflector) and (wafer or	EPO; JPO;	
		substrate or sample)) and (control\$4 near	DERWENT;	
		signal)	IBM_TDB	
20	5	(((((electron or charged-particle or	USPAT;	2004/04/04
		(charged adj particle)) near (beam or expos\$4)) and deflector) and (wafer or	US-PGPUB; EPO; JPO;	14:41
		substrate or sample)) and (control\$4 near	DERWENT;	
		signal)) and (control\$4 near signal near	IBM TDB	
		storage)	_	
21	17	Hashimoto near Shin-Ichi	USPAT;	2004/04/04
	1		US-PGPUB; EPO; JPO;	14:41
			DERWENT;	
	1		IBM_TDB	
22	6121	(((electron or charged-particle or	USPĀT;	2004/04/04
		(charged adj particle)) near beam) and	US-PGPUB;	14:50
		deflect\$4 and control\$4) and (control\$4	EPO; JPO; DERWENT;	1
		near2 signal)	IBM TDB	1
23	103	((((electron or charged-particle or	USPAT;	2004/04/04
		(charged adj particle))near beam) and	US-PGPUB;	16:59
		deflect\$4 and control\$4) and (control\$4	EPO; JPO;	
		near2 signal)) and (stor\$4 near ((control	DERWENT;	
24	37	or deflect\$4) near2 (output or signal))) (((((electron or charged-particle or	IBM_TDB USPAT;	2004/04/04
44	3/	(((((election of charged-particle of charged adj particle))near beam) and	US-PGPUB;	14:51
		deflect\$4 and control\$4) and (control\$4	EPO; JPO;	
1		near2 signal)) and (stor\$4 near ((control	DERWENT;	
		or deflect\$4) near2 (output or signal))))	IBM_TDB	
		and (deflect\$5 near control\$4)	<u> </u>	L

		· · · · · · · · · · · · · · · · · · ·		0004/04/03
25	16	<pre>((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near2 signal)) and (stor\$4 near ((control or deflect\$4) near2 (output or signal))))</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04
26	10	<pre>and (deflect\$5 near control\$4)) and (substrate or wafer or semiconductor) (((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near2 signal)) and (stor\$4 near ((control or deflect\$4) near2 (output or signal))))</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:45
27	7	<pre>and (deflect\$5 near control\$4)) and (substrate or wafer or semiconductor)) and (electrode or deflector) (((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/04 16:45
28	150	<pre>near2 signal)) and (stor\$4 near ((control or deflect\$4) near2 (output or signal)))) and (deflect\$5 near control\$4)) and (substrate or wafer or semiconductor)) and (electrode or deflector)) and register (((electron or charged-particle or</pre>	IBM_TDB	2004/04/04
20	130	(charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	16:50
29	46	<pre>((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04
30	18	<pre>((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))) and expos\$4</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:51
31	13	<pre>((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))) and expos\$4) and (wafer or substrate or sample or semiconductor)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:51
32	6	<pre>(((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))) and expos\$4) and (wafer or substrate or sample or semiconductor)) and switch\$4</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:53
34	1	l 	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:52

				1 2 2 2 1 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2
33	3	<pre>((((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/04 16:52
		two) near4 (beam or beamlet))) and expos\$4) and (wafer or substrate or sample or semiconductor)) and switch\$4) and binary	12.1_122	
35	5	<pre>((((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))) and expos\$4) and (wafer or substrate or sample or semiconductor)) and (clock or timer or timing)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04
36	2	<pre>((((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))) and expos\$4) and (wafer or substrate or sample or semiconductor)) and (clock or timer or timing)) and (shift near register)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:57
37		<pre>((((((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))) and expos\$4) and (wafer or substrate or sample or semiconductor)) and (clock or timer or timing)) and (shift near register)) and (flipflop\$4 or (flip adj flop) or flip-flop\$4)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:55
38	1	(((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))) and expos\$4) and (wafer or substrate or sample or semiconductor)) and (clock or timer or timing)) and (flipflop\$4 or (flip adj flop) or flip-flop\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:58
39	3	<pre>((((((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (stor\$4 near4 deflect\$4 near4 (signal or output))) and ((plurality or multiple or two) near4 (beam or beamlet))) and expos\$4) and (wafer or substrate or sample or semiconductor)) and (shift near register)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:56
40	1	l	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 16:56

41	1	((((((electron or charged-particle or	USPAT;	2004/04/04
		(charged adj particle))near beam) and	US-PGPUB;	16:57
		deflect\$4 and control\$4) and (stor\$4	EPO; JPO;	
		near4 deflect\$4 near4 (signal or	DERWENT;	
		output))) and ((plurality or multiple or	IBM_TDB	
		two) near4 (beam or beamlet))) and		
		expos\$4) and (wafer or substrate or		
		sample or semiconductor)) and (flipflop\$4		
		or (flip adj flop) or flip-flop\$4)		
42	28	((((electron or charged-particle or	USPAT;	2004/04/04
142	20	(charged adj particle)) near beam) and	US-PGPUB;	16:57
				10.57
		deflect\$4 and control\$4) and (stor\$4	EPO; JPO;	
		near4 deflect\$4 near4 (signal or	DERWENT;	
		output))) and (flipflop\$4 or (flip adj	IBM_TDB	
		flop) or flip-flop\$4)		
43	7	<pre>(((((electron or charged-particle or</pre>	USPAT;	2004/04/04
		(charged adj particle))near beam) and	US-PGPUB;	16:59
		deflect\$4 and control\$4) and (stor\$4	EPO; JPO;	
		near4 deflect\$4 near4 (signal or	DERWENT;	
İ		output))) and (flipflop\$4 or (flip adj	IBM TDB	
		flop) or flip-flop\$4)) and ((plurality or	12122	
44	3	<pre>multiple or two) near4 (beam or beamlet)) (((((electron or charged-particle or</pre>	USPAT;	2004/04/04
44	3			
		(charged adj particle)) near beam) and	US-PGPUB;	16:58
		deflect\$4 and control\$4) and (stor\$4	EPO; JPO;	
		near4 deflect\$4 near4 (signal or	DERWENT;	
		output))) and (flipflop\$4 or (flip adj	IBM_TDB	,
		flop) or flip-flop\$4)) and ((plurality or		
		multiple or two) near4 (beam or		
		beamlet))) and (shift near register)		
45	68	((250/492.22,492.2,492.3).CCLS.) and	USPAT;	2004/04/04
10	"	(shift near register)	US-PGPUB;	16:58
		(Shill feat legister)	EPO; JPO;	13.33
			DERWENT;	
		///050/400 00 400 0 400 0) ggtg)	IBM_TDB	2004/04/04
46	13	(((250/492.22,492.2,492.3).CCLS.) and	USPAT;	2004/04/04
		(shift near register)) and (flipflop\$4 or	US-PGPUB;	16:58
		(flip adj flop) or flip-flop\$4)	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
48	1	(((((250/492.22,492.2,492.3).CCLS.) and	USPAT;	2004/04/04
		(shift near register)) and (flipflop\$4 or	US-PGPUB;	17:25
[1	(flip adj flop) or flip-flop\$4)) and	EPO; JPO;	
		((plurality or multiple or two) near4	DERWENT;	
		(beam or beamlet))) and (stor\$4 near	IBM TDB	
	[((control or deflect\$4) near2 (output or		
47		signal)))	IICDATI -	2004/04/04
47	7	((((250/492.22,492.2,492.3).CCLS.) and	USPAT;	' '
		(shift near register)) and (flipflop\$4 or	US-PGPUB;	17:00
		(flip adj flop) or flip-flop\$4)) and	EPO; JPO;	
		((plurality or multiple or two) near4	DERWENT;	
1		(beam or beamlet))	IBM_TDB	
49	5	(((((250/492.22,492.2,492.3).CCLS.) and	USPAT;	2004/04/04
		(shift near register)) and (flipflop\$4 or	US-PGPUB;	17:00
		(flip adj flop) or flip-flop\$4)) and	EPO; JPO;	
]		((plurality or multiple or two) near4	DERWENT;	
	[(beam or beamlet))) and deflect\$4	IBM TDB	
50	5	((((((250/492.22,492.2,492.3).CCLS.) and	USPAT;	2004/04/04
~~		(shift near register)) and (flipflop\$4 or	US-PGPUB;	17:00
		(flip adj flop) or flip-flop\$4)) and	EPO; JPO;	= / • • •
]		((plurality or multiple or two) near4	DERWENT;	
		(beam or beamlet))) and deflect\$4) and	IBM_TDB	
		stor\$4		
51	5	(((((((250/492.22,492.2,492.3).CCLS.) and	USPAT;	2004/04/04
]		(shift near register)) and (flipflop\$4 or	US-PGPUB;	17:01
		(flip adj flop) or flip-flop\$4)) and	EPO; JPO;	
j]	((plurality or multiple or two) near4	DERWENT;	
]		(beam or beamlet))) and deflect\$4) and	IBM TDB	
		stor\$4) and (clock or timer or timing)		
1	11	Table of the control		1

			TIOD N. III	12004/04/04
52	2	<pre>((((((((((250/492.22,492.2,492.3).CCLS.) and (shift near register)) and (flipflop\$4 or (flip adj flop) or flip-flop\$4)) and ((plurality or multiple or two) near4 (beam or beamlet))) and deflect\$4) and stor\$4) and (clock or timer or timing)) and (stor\$4 near5 deflect\$4)</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 17:02
53	3	· · · · · · · · · · · · · · · · · · ·	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 17:02
54	86	((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4 and (control\$4 near4 signal near4 stor\$4)) and (stor\$4 near4 (deflect\$4))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 17:26
55	42	<pre>(((((electron or charged-particle or (charged adj particle))near beam) and deflect\$4 and control\$4) and (control\$4 near4 signal near4 stor\$4)) and (stor\$4 near4 (deflect\$4))) and binary</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/04
56	34		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04
58	1	·	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 17:27
57	3	l	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/04 17:28